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Application/Control No.	Applicant(s)/Patent under Reexamination
10/809,418	HASUNUMA ET AL.
Examiner	Art Unit
Long Pham	2814

	SEARCHED		
Class	Subclass	Date	Examiner
257	701,709 758	1/8/2006	LP

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
257	758	1/8/2006	LP
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SEARCH I (INCLUDING SEAR	NOTES CH STRATEGY	′)
	DATE	EXMR
text searches updated	1/8/2006	LP